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Supporting Information

for

On the transformation of “zincone”-like into porous ZnO thin films from sub-saturated plasma enhanced atomic layer deposition

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Details on the EP measurements, GIXD data recorded after annealing at 600 °C, saturation curves for the PE-ALD ZnO process optimized at room temperature, example of fitting of the HR XPS peak associated to O 1s

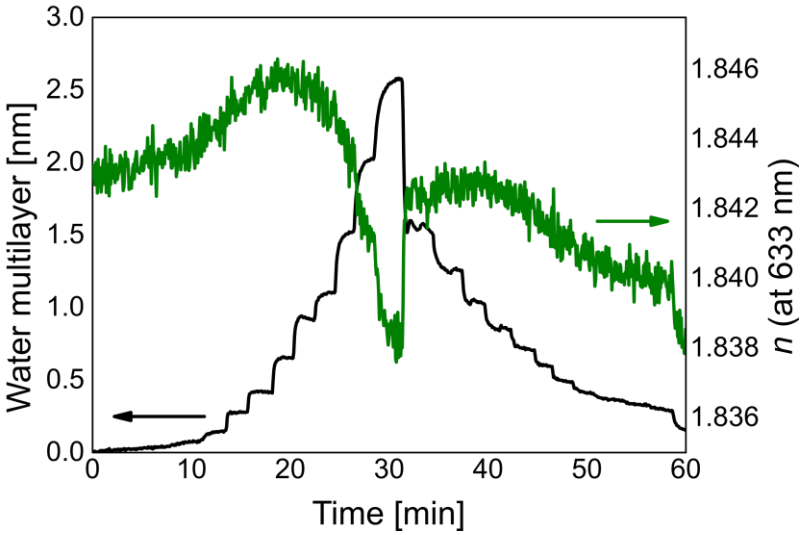

Figure S1: Example of the ellipsometric porosimetry measurement performed on an annealed ZnO layer. The water multilayer thickness and the refractive index are here reported as a function of time.

The relative humidity was changed step by step in the range 0–95%.

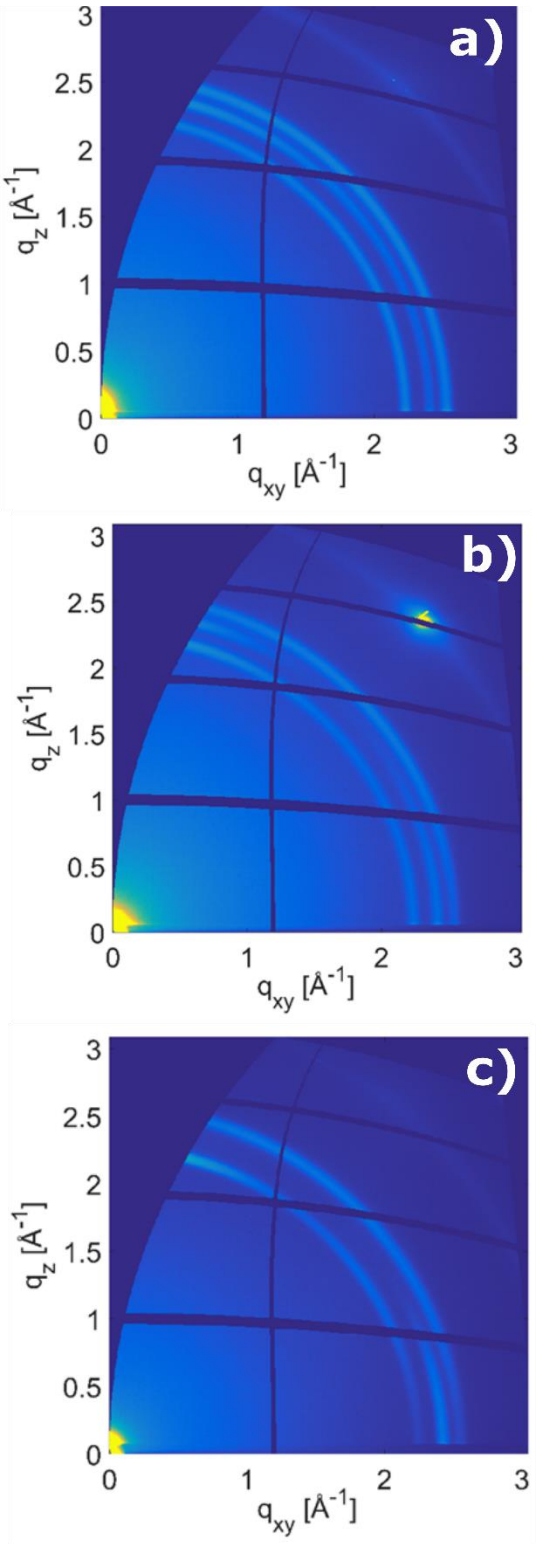

Figure S2: GIXD maps for the zincone-like layers deposited at different plasma times after annealing at 600 °C: a) 1 s b) 2 s and c) 4 s plasma time.

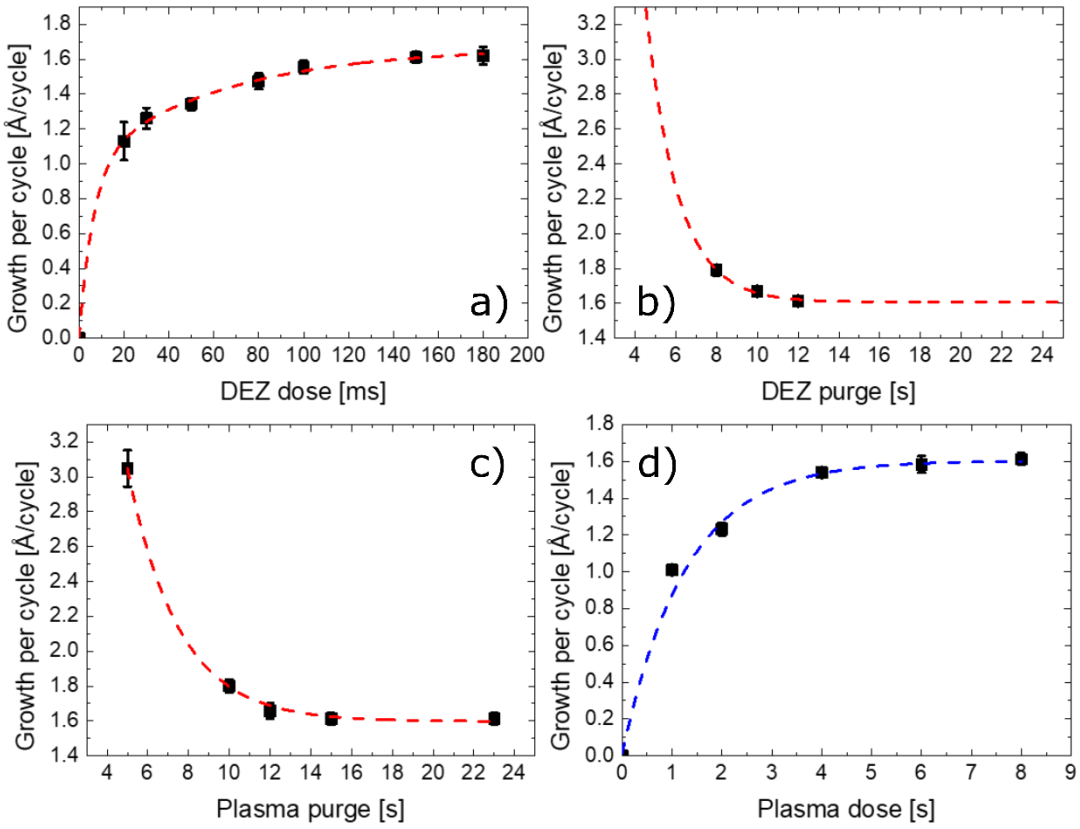

Figure S3: Saturation curves for the PE-ALD ZnO used in this manuscript. a) DEZ dose, b) DEZ purge, c) plasma purge, d) plasma dose, also shown in Figure 1 in the manuscript.

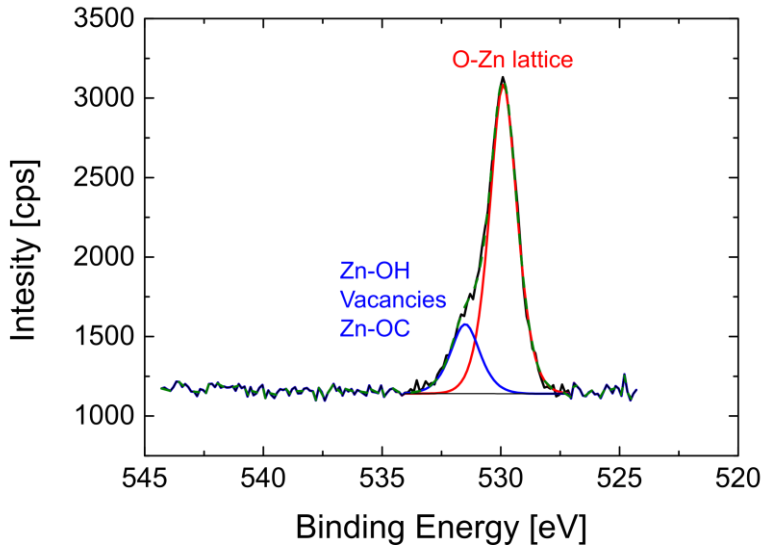

Figure S4: Example of fitting of the HR XPS peak associated to O 1s. the attribution of the peaks is also reported in the plot.